

PB6500

The PB6500 is the ideal analyzer for all probe card technologies. Its user friendly software and optical set-up allow it to be easily configured to capture all types of probe tips currently in use, including cantilever needle, vertical, MEMS, membrane and pogo style probes. Its excellent electrical measurement system and the ability to drive relays, FET's or optical switches on any channel make it the best tool for testing probe cards with complex circuitry. With 200 Kg of lift force, it has long been recognized as the analyzer of choice for vertical probe card and other high-force probe card users and manufacturers. Probilt's large measurement chuck allows probe arrays as large as 8"x 8" to be touched down without overhanging the chuck surface.

PB6800

Probilt's PB6800 large measurement chuck is the ideal solutions for analyzing single touchdown memory array probe cards. It allows probe arrays as large as 300 mm in diameter to be touched down without overhanging the chuck surface.

The PB6800 has all the same electrical test features of the PB6500 including the option to increase the number of measurement channels to 12,032. All channels can be software controlled to be either a test channel or a relay drive channel. With 200Kg's of lift force it can easily replicate the same environment the probe card sees when installed on the production wafer probe system.

PB6800 LT

The PB6800LT is a 12,032 channel tester designed to test the electrical leakage on large probe heads and probe card pcb's. Designed as an in-process tool for the probe card manufacturer it will enhance final analyzer test throughput by guaranteeing the probe card sub-components are within specification for electrical leakage before the finished probe card is put on final test. The PB6800LT has the same easy to use software and user interface as all other Probilt products.

PB6800 FWC

The PB6800FWC has been specifically designed to analyze wafer probe products used in full wafer test and burn-in. Based on the successful PB6800 platform it has additional features that allow it to completely test the electrical and mechanical integrity of these Full Wafer Contactors. The PB6800FWC has the same easy to use software and user interface as all other Probilt products.

PB6800 PA

The PB6800PA is designed to provide a low cost alignment test station for 300mm probe arrays, as well as individual probe planarity. The PB6800PA can be used in-process by probe card manufacturers to improve probe card build quality, or as a stand alone alignment test station. The PB6800PA utilizes the same production proven optical system used in the successful PB6800 probe card analyzer. The PB6800PA has the same easy to use software and user interface as all other Probilt products.

PB6800 PRL

The PB6800PRL is designed primarily for use by probe card manufacturers as an in process tool or in conjunction with the PB6800PA. It allows the user to tilt correct the probe head, run signal planarity and contact resistance and test the electrical leakage of the probe card. The PB6800PRL can have up to 12,032 test channels. The PB6800PRL has the same easy to use software and user interface as all other Probilt products.

PB1200 - probe card analyzer and repair

The PB1200 is an automated probe card repair system. It has the capability to fully test alignment, planarity and (optionally) gram force, with its main benefits being improvements to probe card repair speed and accuracy or as an in-process tool for manufacturers of fine pitch epoxy ring probe cards. This system is designed for stand alone use and as a companion tool for the higher-end probe card analyzers. The probe card is tested and repaired in a “tips up” position which eliminates the time to flip from test to repair position.

PB1500 - low cost probe card analyzer

The PB1500 is a low cost probe card analyzer system. It has the capability to perform all the tests done on the larger PB3600/6500 probe card analyzers, but at a lower cost for low pincount cards. A maximum of 1,280 channels may be configured in the PB1500 MUX system.

This bench-top analyzer is a totally new concept in probe card test and repair. This system is designed for stand alone use and as a companion tool for the higher end probe card analyzers. The probe card is tested and repaired in a “tips up” position which eliminates the time to flip from test to repair position.

PB3600 - probe card analyzer

The PB3600 is a mid-range probe card analyzer for test and repair of all probe technologies currently available. It can be configured to have a maximum of 3072 measurement channels which can be software controlled to be either a test channel or a relay drive channel. When configured with the unique ProbeTracker, software controlled microscope drive it is the ideal tool for test and repair of probe cards designed to test mixed signal, LCD driver and microcontroller devices.

Motherboards

Lightweight, easy to install

- Accurate correlation to wafer prober
- Full 4-wire Kelvin for all channels
- Fast design & delivery
 - Standard parts inventory
 - Custom layout programs

ITC designs and manufactures hundreds of motherboard types including interfaces to all major brands and types of testers, including:

- Advantest – T5375/77, T5383, ND1, ND2
- Verigy– V4400, V5400, 93000, 93000 Pinscale
- Teradyne – Integra/Flex/Tiger, J750
- Credence – Kalos, MT32, MT72, Sapphire
- Yokogawa – AL6050, 6700, MT6060
- NexTest – Maverick HD, Magnum GV
- TI - VLCT, RASP
- LTX - Fusion

INTEGRATED TECHNOLOGY CORPORATION

1228 North Stadem Drive • Tempe, Arizona 85281 USA • Phone 480-968-3459 • Fax 480-968-3099

Sales@IntTechCorp.com